## Search Notes



Applicant(s)/Patent Under Reexamination

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Examiner SHANE FANG

Art Unit

SEARCHEI	

Application/Control No.

SEARCHED				
Class	Subc	lass	Date	Examiner
528	422	12	2/14/2009	sf

SEARCH NOTES		
Search Notes	Date	Examiner
NPL and STIC searched	12/14/2009	sf
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	INTERFERENCE SEA	RCH	
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